

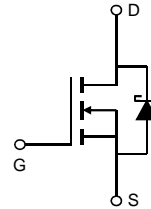
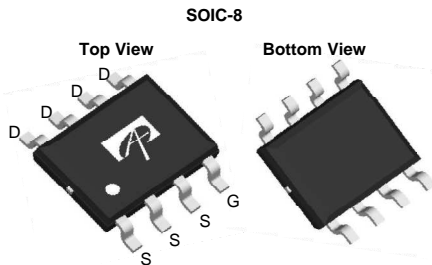
General Description

SRFET™ AO4712 uses advanced trench technology with a monolithically integrated Schottky diode to provide excellent $R_{DS(ON)}$, and low gate charge. This device is suitable for use as a low side FET in SMPS, load switching and general purpose applications.

Product Summary

V_{DS}	30V
I_D (at $V_{GS}=10V$)	13A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 11mΩ
$R_{DS(ON)}$ (at $V_{GS} = 4.5V$)	< 14mΩ

100% UIS Tested
 100% R_g Tested



SRFET™
 Soft Recovery MOSFET:
 Integrated Schottky Diode

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	±12	V
Continuous Drain Current	I_D	$T_A=25^\circ C$	13
		$T_A=70^\circ C$	10
Pulsed Drain Current ^C	I_{DM}	68	A
Avalanche Current ^C	I_{AS}, I_{AR}	15	A
Avalanche energy $L=0.1mH$ ^C	E_{AS}, E_{AR}	11	mJ
Power Dissipation ^B	P_D	$T_A=25^\circ C$	3.1
		$T_A=70^\circ C$	2
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	32	40	°C/W
Maximum Junction-to-Ambient ^{A, D}		60	75	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	17	24	°C/W

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =1mA, V _{GS} =0V	30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} =0V T _J =125°C			0.5 100	mA
I _{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} = ±12V			100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.1	1.65	2.1	V
I _{D(ON)}	On state drain current	V _{GS} =10V, V _{DS} =5V	68			A
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =13A T _J =125°C		9 13	11 16	mΩ
		V _{GS} =4.5V, I _D =11A		10.7	14	mΩ
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =13A		80		S
V _{SD}	Diode Forward Voltage	I _S =1A, V _{GS} =0V		0.4	0.7	V
I _S	Maximum Body-Diode Continuous Current				5	A
DYNAMIC PARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =15V, f=1MHz	930	1170	1400	pF
C _{oss}	Output Capacitance		90	128	170	pF
C _{riss}	Reverse Transfer Capacitance		45	89	125	pF
R _g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz	0.7	1.4	2.1	Ω
SWITCHING PARAMETERS						
Q _{g(10V)}	Total Gate Charge	V _{GS} =10V, V _{DS} =15V, I _D =13A	16	20	24	nC
Q _{g(4.5V)}	Total Gate Charge		7	8.7	10.5	nC
Q _{gs}	Gate Source Charge			3.2		nC
Q _{gd}	Gate Drain Charge			3		nC
t _{D(on)}	Turn-On DelayTime	V _{GS} =10V, V _{DS} =15V, R _L =1.2Ω, R _{GEN} =3Ω		6		ns
t _r	Turn-On Rise Time			2.4		ns
t _{D(off)}	Turn-Off DelayTime			23		ns
t _f	Turn-Off Fall Time			4		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =13A, dI/dt=500A/μs	5.5	7	8.5	ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =13A, dI/dt=500A/μs	5	6.5	8	nC

A. The value of R_{θJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on T_{J(MAX)}=150° C, using ≤ 10s junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150° C. Ratings are based on low frequency and duty cycles to keep initial T_J=25° C.

D. The R_{θJA} is the sum of the thermal impedance from junction to lead R_{θJL} and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of T_{J(MAX)}=150° C. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

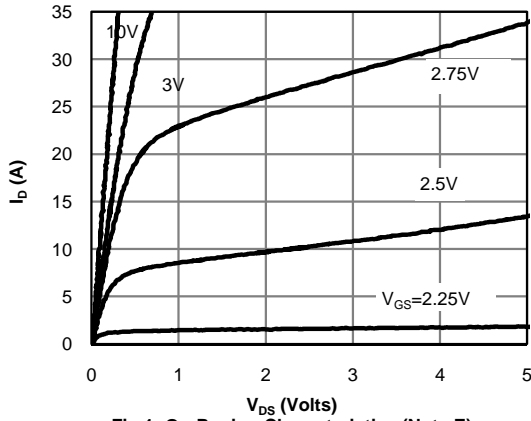


Figure 1: On-Region Characteristics (Note E)

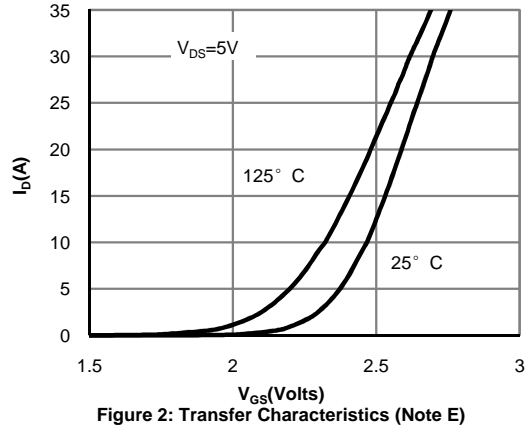


Figure 2: Transfer Characteristics (Note E)

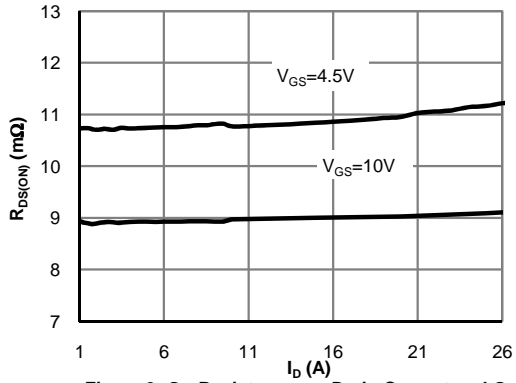


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

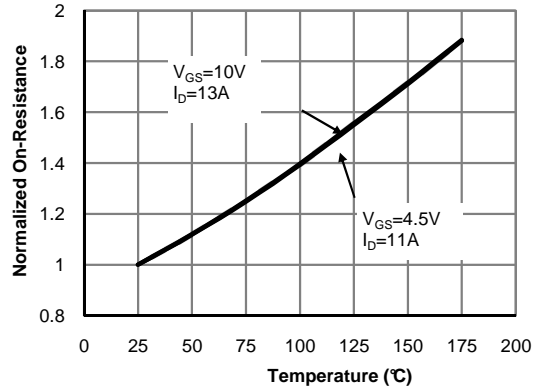


Figure 4: On-Resistance vs. Junction Temperature (Note E)

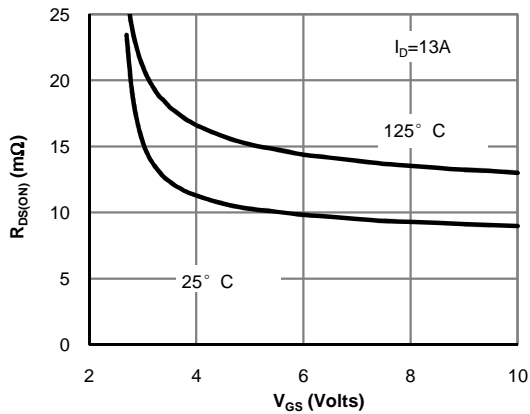


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

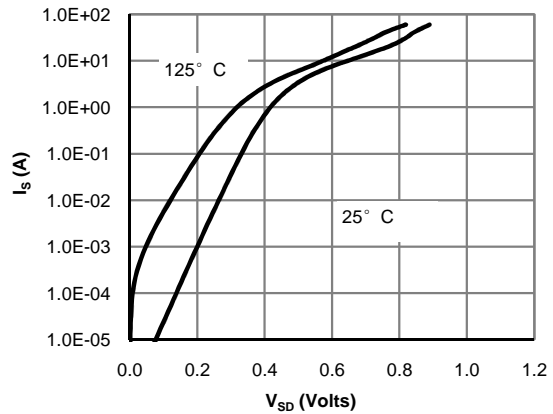


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

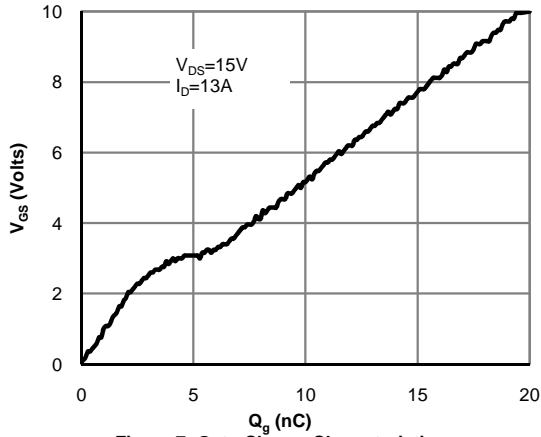


Figure 7: Gate-Charge Characteristics

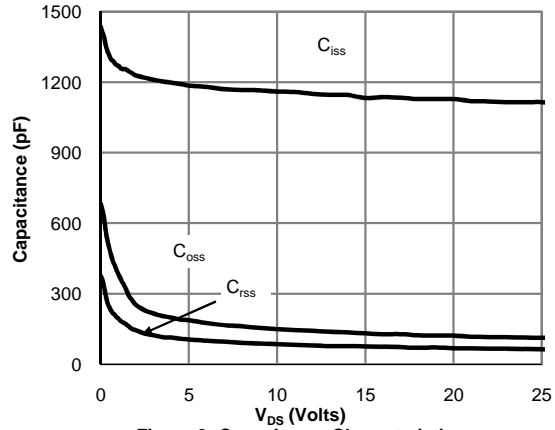


Figure 8: Capacitance Characteristics

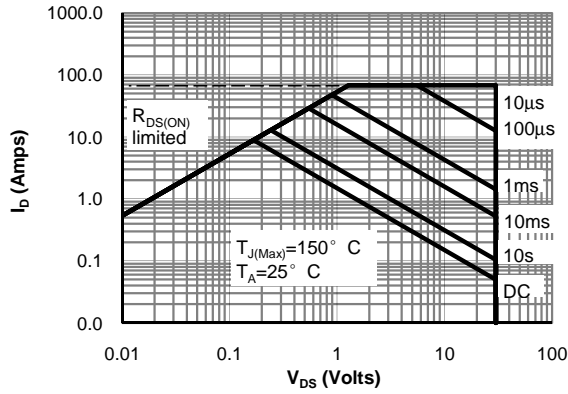


Figure 10: Maximum Forward Biased Safe Operating Area (Note F)

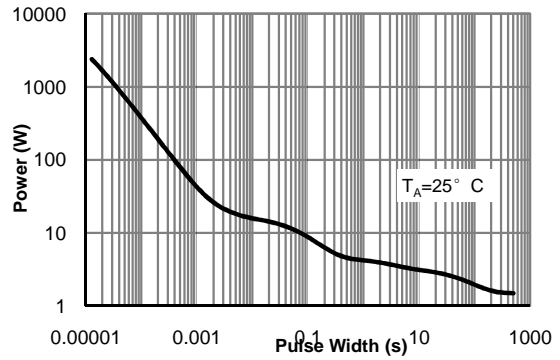


Figure 11: Single Pulse Power Rating Junction-to-Ambient (Note F)

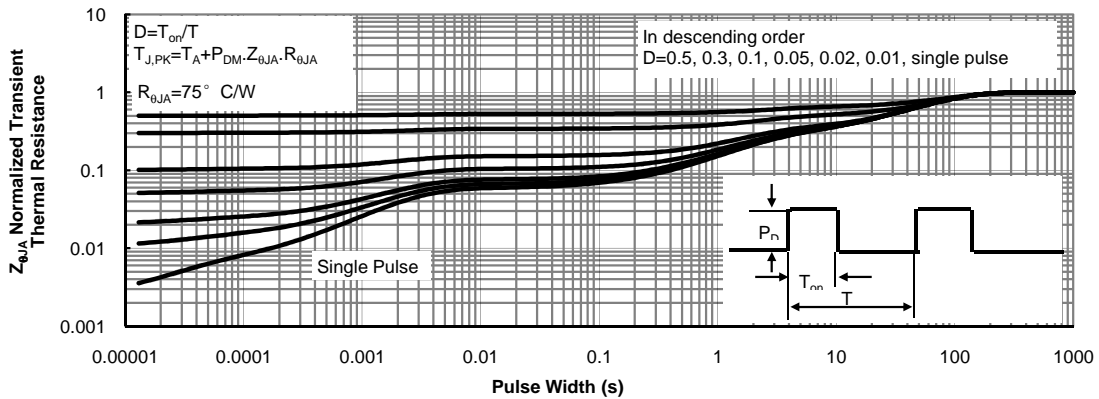


Figure 12: Normalized Maximum Transient Thermal Impedance (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

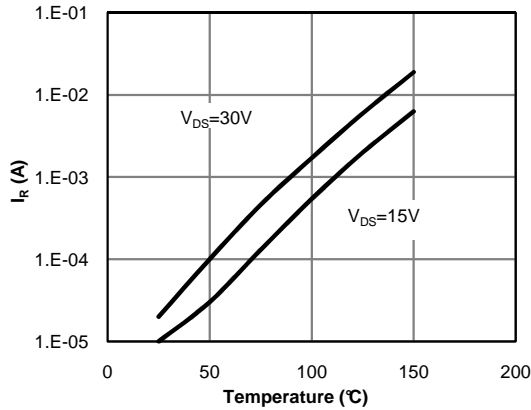


Figure 13: Diode Reverse Leakage Current vs. Junction Temperature

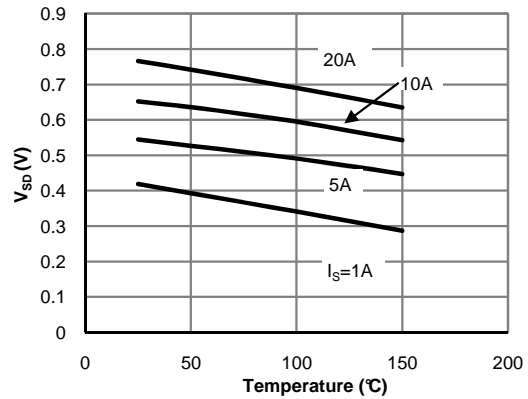


Figure 14: Diode Forward Voltage vs. Junction Temperature

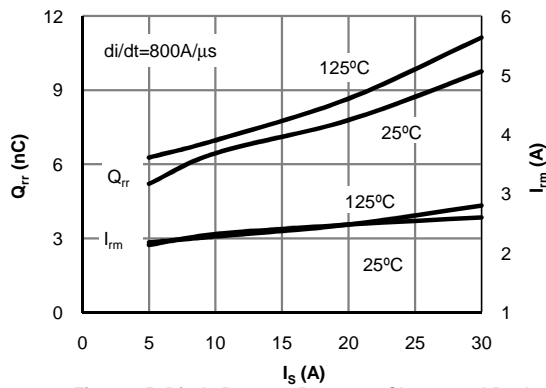


Figure 15: Diode Reverse Recovery Charge and Peak Current vs. Conduction Current

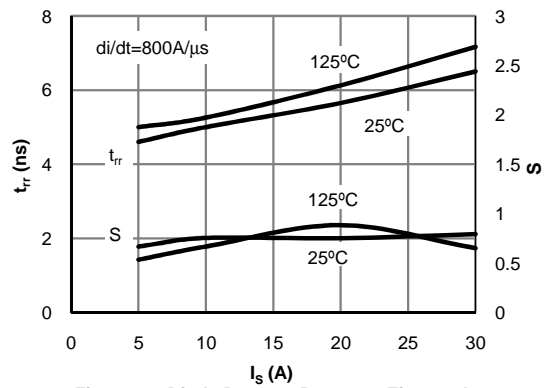


Figure 16: Diode Reverse Recovery Time and Softness Factor vs. Conduction Current

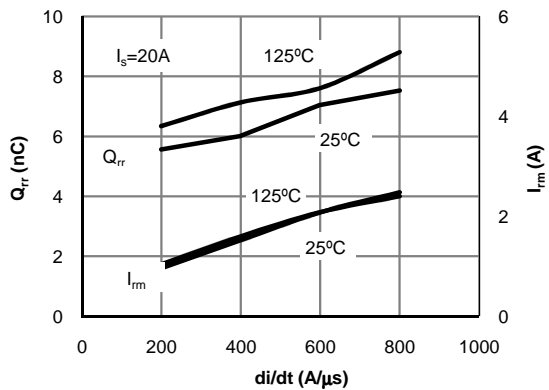


Figure 17: Diode Reverse Recovery Charge and Peak Current vs. di/dt

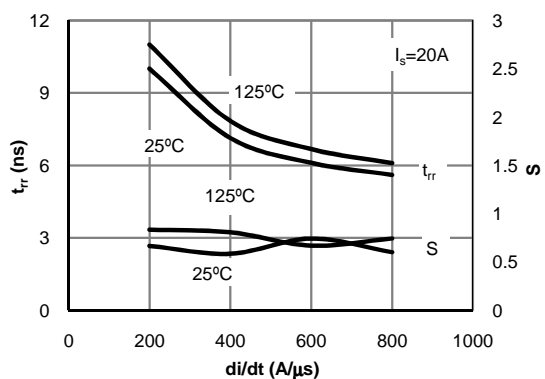
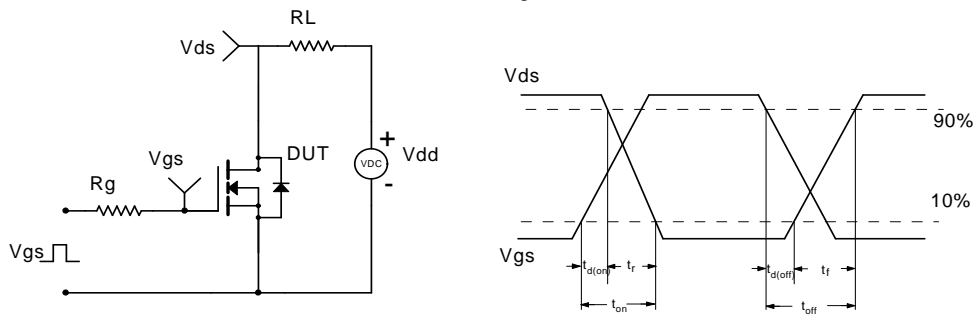


Figure 18: Diode Reverse Recovery Time and Softness Factor vs. di/dt

Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

